

<b>Notice of References Cited</b>	Application/Control No. 09/487,729	Applicant(s)/Patent Under Reexamination HAN, BAIK-HEE	
	Examiner Paulos M. Natnael	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5034819	07-1991	Tsukagoshi	348/732
	B	US-5512955	04-1996	Toyoshima et al.	348/569
	C	US-5410361	04-1995	Lee	348/570
	D	US-5771080	06-1998	Sakakibara	348/731
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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